

OFGS File No. P/3541-7 Application 109/651,770 Applicant Tatsuji HIGUCHI, et al. APPLICANT'S ART CITATION Group Art Unit 2623 2615 (Use several sheets if necessary) Filing Date 8/30/00 U.S. PATENT DOCUMENTS Examiner Sub-Filing Date Initial class If Appropriate **Document Number** Date ' Name Class RECEIVED **Technology Center 2600** FOREIGN PATENT DOCUMENTS Translation Document Number Class Date Country Sub-Yes N class 0 10 5 2 3 9/29/1998 X 6 Japan (SEE JP OFFICE ACTION) 5/28/1999 6 3 11 1 Japan X (SEE JP OFFICE Астюм) OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Japanese Office Action dated August 27, 2002. Examiner Date Considered

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